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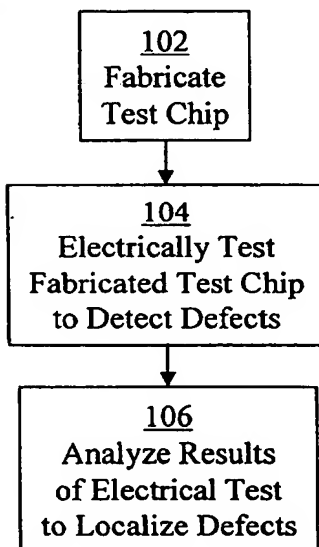
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(54) Title: FAST LOCALIZATION OF ELECTRICAL FAILURES ON AN INTEGRATED CIRCUIT SYSTEM AND METHOD

(57) Abstract: Fast localization of electrically measured defects of integrated circuits includes providing information for fabricating a test chip having test structures configured for parallel electrical testing. The test structures on the test chip are electrically tested employing a parallel electrical tester. The results of the electrical testing are analyzed to localize defects on the test chip.



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